# NDBA070N10B

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Advance Information

# Power MOSFET 100V, 10.5mΩ, 70A, N-Channel

#### **Features**

- Low On-Resistance
- Low Gate Charge
- High Speed Switching
- 100% Avalanche Tested
- Pb-Free, Halogen Free and RoHS Compliance

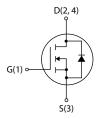
# VDSS RDS(on) Max ID Max 100V 10.5 mΩ@15V 70A 12.4 mΩ@10V 70A

# **Specifications**

### **Absolute Maximum Ratings** at Ta = 25°C

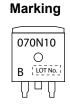
Parameter	Symbol	Value	Unit
Drain to Source Voltage	V <sub>DSS</sub>	100	V
Gate to Source Voltage	V <sub>GSS</sub>	±20	V
Drain Current (DC)	ID	70	Α
Drain Current (Pulse) PW≤10μs, duty cycle≤1%	IDP	280	Α
Power Dissipation Tc=25°C	PD	72	W
Junction Temperature	Tj	175	°C
Storage Temperature	Tstg	–55 to +175	°C
Source Current (Body Diode)	Is	70	Α
Avalanche Energy (Single Pulse) *1	EAS	82	mJ
Lead Temperature for Soldering Purposes, 3mm from Case for 10 Seconds	TL	260	°C

# Electrical Connection N-Channel

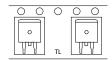




TO-263 CASE 418AJ



#### Packing Type:TL



# **Thermal Resistance Ratings**

Parameter	Symbol	Value	Unit
Junction to Case Steady State	$R_{\theta JC}$	2.08	0000
Junction to Ambient *2	$R_{\theta JA}$	62.5	°C/W

Note : \*1  $V_{\mbox{\scriptsize DD}}\!\!=\!\!48\mbox{\scriptsize V},$  L=100 $\mu\mbox{\scriptsize H},$  IAV=30A (Fig.1)

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

This document contains information on a new product. Specifications and information herein are subject to change without notice.

#### **ORDERING INFORMATION**

See detailed ordering and shipping information on page 5 of this data sheet.

<sup>\*2</sup> Surface mounted on FR4 board using recommended footprint

## NDBA070N10B

#### **Electrical Characteristics** at Ta = 25°C

Parameter	Cumbal	- Condition	Value		1114	
Parameter	Symbol	Conditions	min	typ	max	Unit
Drain to Source Breakdown Voltage	V(BR)DSS	I <sub>D</sub> =10mA, V <sub>GS</sub> =0V	100			V
Zero-Gate Voltage Drain Current	IDSS	V <sub>DS</sub> =100V, V <sub>GS</sub> =0V			1	μΑ
Gate to Source Leakage Current	IGSS	V <sub>GS</sub> =±20V, V <sub>DS</sub> =0V			±100	nA
Gate Threshold Voltage	V <sub>GS</sub> (th)	V <sub>DS</sub> =10V, I <sub>D</sub> =1mA	2		4	V
Forward Transconductance	9FS	V <sub>DS</sub> =10V, I <sub>D</sub> =35A		50		S
Static Drain to Source On-State Resistance	R <sub>DS</sub> (on)1	I <sub>D</sub> =35A, V <sub>GS</sub> =15V		8.7	10.5	mΩ
	R <sub>DS</sub> (on)2	I <sub>D</sub> =35A, V <sub>GS</sub> =10V		9.5	12.4	mΩ
Input Capacitance	Ciss			2,010		pF
Output Capacitance	Coss	V <sub>DS</sub> =50V, f=1MHz		840		pF
Reverse Transfer Capacitance	Crss			21		pF
Turn-ON Delay Time	t <sub>d</sub> (on)			30		ns
Rise Time	t <sub>r</sub>			180		ns
Turn-OFF Delay Time	t <sub>d</sub> (off)	See Fig.2		55		ns
Fall Time	tf			40		ns
Total Gate Charge	Qg			26		nC
Gate to Source Charge	Qgs	V <sub>DS</sub> =48V, V <sub>GS</sub> =10V, I <sub>D</sub> =70A		9		nC
Gate to Drain "Miller" Charge	Qgd			8		nC
Forward Diode Voltage	V <sub>SD</sub>	I <sub>S</sub> =70A, V <sub>GS</sub> =0V		1.1	1.5	V
Reverse Recovery Time	t <sub>rr</sub>	See Fig.3		95		ns
Reverse Recovery Charge	Q <sub>rr</sub>	I <sub>S</sub> =70A, V <sub>GS</sub> =0V, di/dt=100A/μs		240		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

Fig.1 Unclamped Inductive Switching Test Circuit

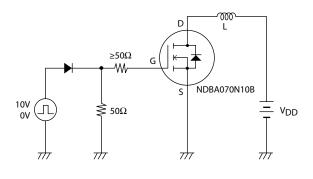


Fig.2 Switching Time Test Circuit

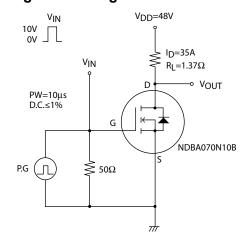
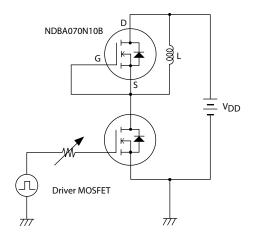
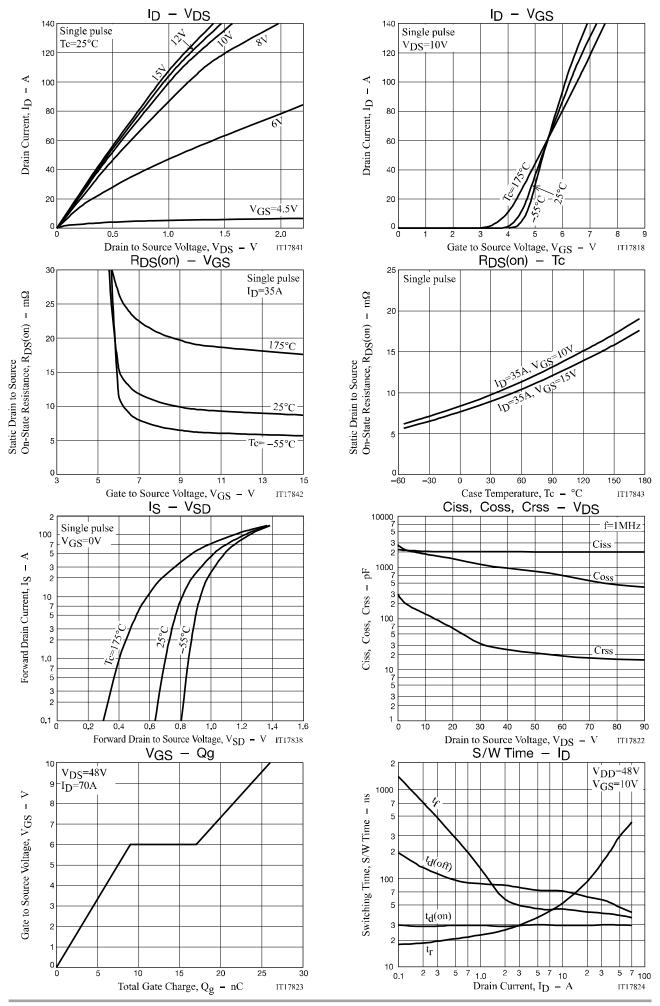
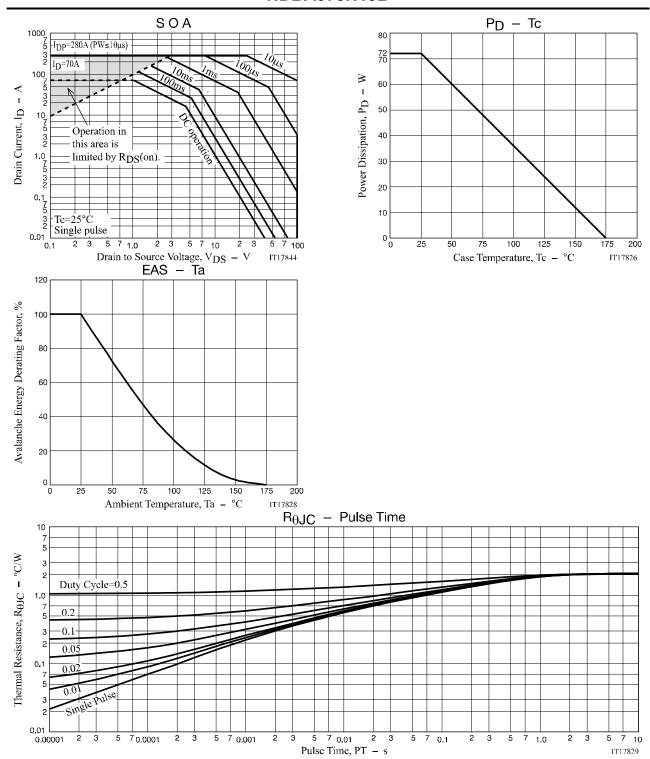


Fig.3 Reverse Recovery Time Test Circuit



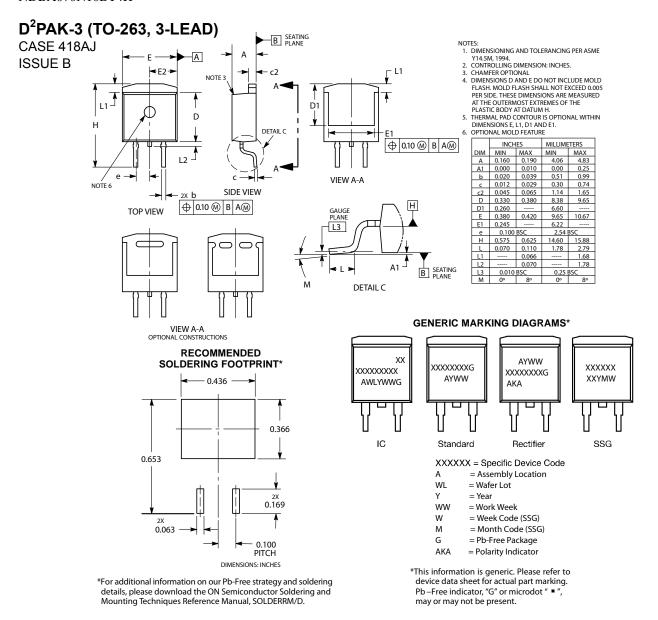


## NDBA070N10B



#### **Package Dimensions**

NDBA070N10BT4H



#### ORDERING INFORMATION

Device	Package	Shipping	note	
NDBA070N10BT4H	TO-263	800 pcs. / reel	Pb-Free and Halogen Free	

Note on usage: Since the NDBA070N10B is a MOSFET product, please avoid using this device in the vicinity of highly charged objects.

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